

IT IS CLAIMED:

1.-6. Cancelled

7. A method, comprising:

receiving a substrate; and

depositing on the substrate a first layer of material having a first secondary emission ratio.

8. The method of claim 7, wherein:

the first secondary emission ratio is associated with a first phase of the first layer, and the first layer has a second phase with an associated second secondary emission ratio.

9. The method of claim 7, further comprising:

depositing on the first layer a second layer having a second secondary emission ratio.

10. The method of claim 9, wherein:

the second secondary emission ratio is greater than the first secondary emission ratio by a factor of at least 10.

11.-15. Cancelled

16. A method, comprising:

receiving electrons at a spot of a first layer of a medium, the first layer disposed above a second layer, the first layer having a first secondary emission ratio, the second layer having a second secondary emission ratio, the first secondary emission ratio differing from the second secondary emission ratio; and

removing a portion of the first layer responsive to receiving the electrons, the portion aligned with the spot.

17. The method of claim 16, wherein:

the portion is ablated during removing the portion of the first layer.

18. The method of claim 16, wherein:

the portion is vaporized during removing the portion of the first layer.

19. The method of claim 16, wherein:

the electrons are further received in an intermediate layer disposed between the first layer and the second layer;

and further comprising:

ablating the intermediate layer in alignment with the spot, the ablating the intermediate layer also removing the first layer.

20. A method, comprising:

projecting electrons from a carbon nanotube at a spot of a first layer of a medium, the first layer disposed above a second layer, the first layer having a first secondary emission ratio, the second layer having a second secondary emission ratio, the first secondary emission ratio differing from the second secondary emission ratio, the number and energy of electrons projected based on an expected amount of energy to remove a portion of the first layer, the portion of the first layer aligned with the spot; and

removing a portion of the first layer responsive to receiving the electrons.

21. The method of claim 20, wherein:

the portion of the first layer is ablated during removing the portion of the first layer.

22. The method of claim 20, wherein:

the portion of the first layer is vaporized during removing the portion of the first layer.

23. The method of claim 20, wherein:

the electrons are further received in an intermediate layer disposed between the first layer and the second layer, the expected amount of energy to remove the first layer includes energy to ablate the intermediate layer;

and further comprising:

ablating the intermediate layer in alignment with the spot, the ablating the intermediate layer also removing the first layer.

24. A method, comprising:

projecting electrons from a carbon nanotube at a spot of a phase change material having a first phase and a second phase, the first phase having associated therewith a first secondary emission ratio, the second phase having associated therewith a second secondary emission ratio; and

absorbing the electrons within a portion of the phase change material, the portion aligned with the spot, the portion in the first phase prior to absorbing the electrons;

changing the portion of the phase change material from the first phase to the second phase responsive to absorbing the electrons.

25. The method of claim 24, further comprising:

cooling the portion of the phase change material quickly after absorbing the electrons.

26. The method of claim 24, further comprising:

cooling the portion of the phase change material slowly after absorbing the electrons.

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